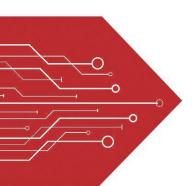
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet

www.msksemi.com

Compiance

Product Summary

V_{DS} 30V
 I_D 60A
 R_{DS(ON)}(at V_{GS}=10V) <9.0mohm
 R_{DS(ON)}(at V_{GS}=4.5V) <11.0mohm

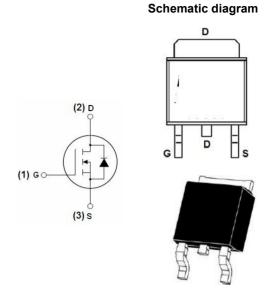
100% UIS Tested100% ∇V_{DS} Tested

General Description

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low R_{DS(ON)}

Applications

- High current load applications
- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply



TO-252

■ Absolute Maximum Ratings (T_A=25°C unless otherwise noted)

Parameter		Symbol	Limit	Unit	
Drain-source Voltage		V _{DS}	30	V	
Gate-source Voltage		V_{GS}	±20	V	
Drain Current	T _c =25℃	l _D	60	А	
Drain Current	T _C =100°C	ID	35		
Pulsed Drain Current ^A		I _{DM}	150	Α	
Total Power Dissipation	T _C =25℃	P _D	34	W	
	T _C =100℃	FD	17	W	
Single Pulse Avalanche Energy ^B		E _{AS}	80	mJ	
Thermal Resistance Junction-to-Case ^C		R _{θJC}	4.4	°C/W	
Junction and Storage Temperature Range		T _J ,T _{STG}	- 55∼+175	$^{\circ}$	

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■ Electrical Characteristics (T_.=25°C unless otherwise noted)

Parameter	Symbol	ol Conditions		Min	Тур	Max	Units
Static Parameter				•	•		,
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D =250μA		30			V
	I _{DSS}	V _{DS} =30V,V _{GS} =0V	T _J =25℃			1	μΑ
Zero Gate Voltage Drain Current			T _J =55℃			5	
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} =0V				±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} = V _{GS} , I _D =250μA		1.0	1.5	2.5	V
Olaffa Paria Courses On Pariateurs	R _{DS(ON)}	V _{GS} = 10V, I _D =15A			6.5	9.0	- mΩ
Static Drain-Source On-Resistance		V _{GS} = 4.5V, I _D =15A			8.6	11.0	
Diode Forward Voltage	V _{SD}	I _S =15A,V _{GS} =0V			0.85	1.2	V
Maximum Body-Diode Continuous Current	Is					50	А
Dynamic Parameters		,					
Input Capacitance	C _{iss}	V _{DS} =15V,V _{GS} =0V,f=1MHZ			920		pF
Output Capacitance	Coss				198		
Reverse Transfer Capacitance	C _{rss}				114		
Switching Parameters		,					
Total Gate Charge	Qg	V _{GS} =10V,V _{DS} =15V,I _D =50A			28		- nC
Gate-Source Charge	Q_{gs}				7		
Gate-Drain Charge	Q_{gd}				5		
Reverse Recovery Charge	Q _{rr}	- I _F =20A, di/dt=100A/us			25		
Reverse Recovery Time	t _{rr}				26		
Turn-on Delay Time	t _{D(on)}	$V_{GS}=10V, V_{DD}=20V, I_{D}=2A, R_{L}=1\Omega$ $R_{GEN}=3\Omega$			8		
Turn-on Rise Time	t _r				15		ns
Turn-off Delay Time	t _{D(off)}				27		
Turn-off fall Time	t _f				7		

A. Pulse Test: Pulse Width \leqslant 300us,Duty cycle \leqslant 2%.

B. T_j =25°C, V_{DD} =20V, V_G =10V, L=0.5mH, R_g =25 Ω

C. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design, while R_{BJA} is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.



■ Typical Performance Characteristics

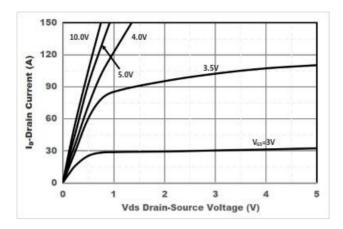


Figure 1. Output Characteristics

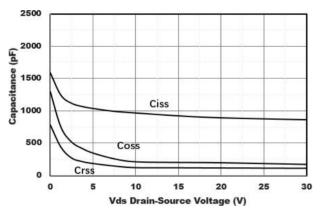


Figure 3. Capacitance Characteristics

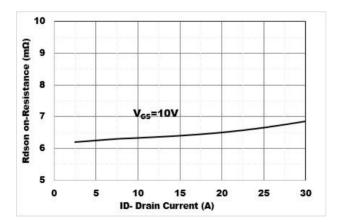


Figure 5. Drain-Source on Resistance

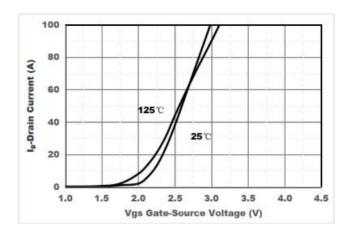


Figure 2. Transfer Characteristics

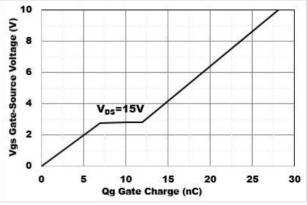


Figure4. Gate Charge

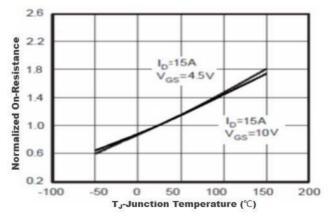


Figure6. Drain-Source on Resistance



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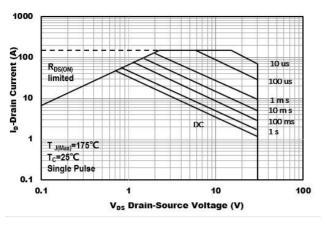


Figure 7. Safe Operation Area

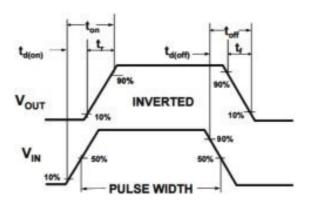
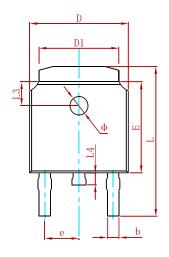
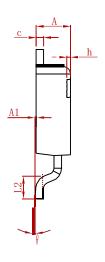


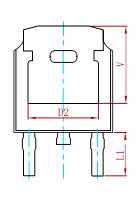
Figure8. Switching wave



PACKAGE MECHANICAL DATA

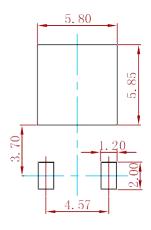






Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	4.830 REF.		REF.	
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900	REF.	0.114	REF.	
L2	1.400	1.700	0.055	0.067	
L3	1.600	REF.	0.063	REF.	
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250	REF.	0.207	REF.	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MS60N03	TO-252	2500



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